

Latest Results on the Radiation Tolerance of Diamond Detectors

29th International Symposium on Lepton Photon Interactions at High Energies

Lukas Bäni on behalf of the RD42 Collaboration

Toronto, 08.08.2019



Motivation

- Present Situation at CERN LHC Experiments
 - Innermost layers → highest particle rate, highest radiation damage
 - Current detectors presently can not withstand the GHz/cm² rate and 2×10^{16} /cm² fluence of the HL-LHC
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 - insulating material with high thermal conductivity
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- **RD42 collaboration** investigates signals and radiation tolerance in various detector designs
 - pad (full diamond as a single cell)
 - strip
 - pixel (diamond sensor on pixel chips)
 - 3D to reduce drift distance → **M. Reichmann's talk**

The RD42 Collaboration

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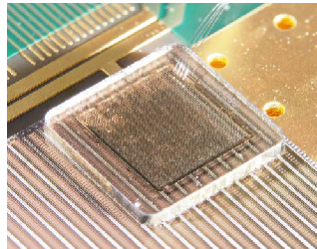
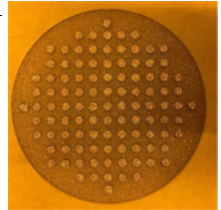
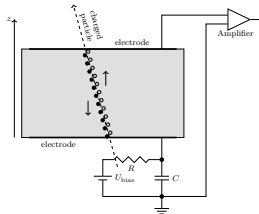
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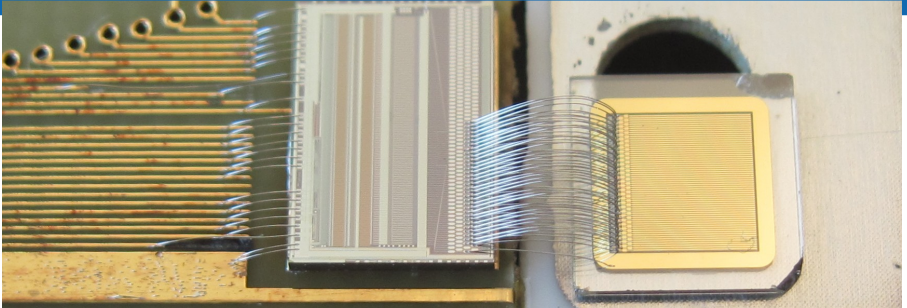
118 Participants

29 Institutes

Diamond as a Particle Detector

- Diamond detectors are operated as ionization chambers
- Poly-crystalline material comes in large wafers
- Metalization on both sides
 - Pad
 - Strip
 - Pixel
- Connected to low noise electronics

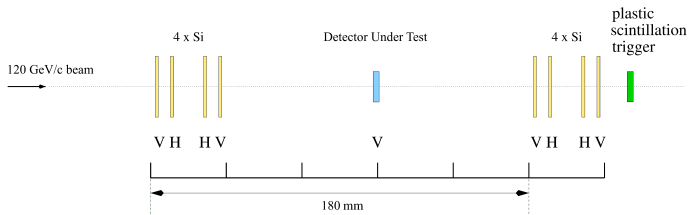




Radiation Tolerance

Study the pulse height dependance on the irradiation fluence

Beam Test Setup



- Irradiate diamond samples with various particle species and energies
- Re-metalize after each irradiation step to fabricate a strip detector
- Characterization of irradiated devices in beam tests
- transparent (unbiased) hit prediction from telescope
- tracking precision at detector under test: $\sim 2\text{--}3\,\mu\text{m}$

Analysis Strategy

- Measure the signal response as a function of predicted position
→ Direct measurement of **charge collection distance (CCD)**
CCD = average distance e-h pairs drift apart under E -field

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- Convert CCD to «**schubweg**» (λ) – the mean free drift distance before being trapped in an infinite material

$$\frac{ccd}{t} = \sum_{i=e,h} \frac{\lambda_i}{t} \left[1 - \frac{\lambda_i}{t} \left(1 - \exp \left(-\frac{t}{\lambda_i} \right) \right) \right]$$

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- Damage equation

$$n = n_0 + k' \phi$$

$$\frac{1}{\lambda} = \frac{1}{\lambda_0} + k \phi$$

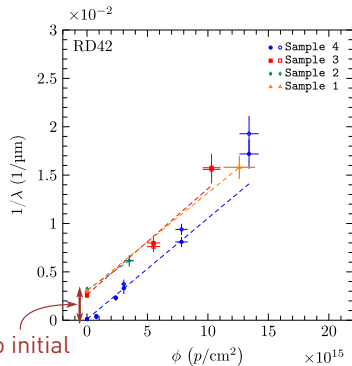
t	thickness
n	number of traps
n_0	initial traps in material
ϕ	fluence
λ	schubweg
λ_0	initial schubweg
k	damage constant

- Fit in **$1/\lambda$ vs ϕ space** to determine k , λ_0

Radiation Tolerance

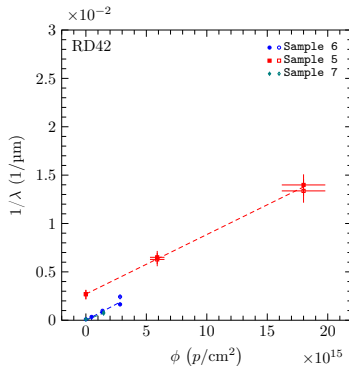
[DOI: 10.1088/1361-6463/ab37c6]

- Plot single- and poly-crystalline data on same graph
- Linear fit in $1/\lambda$ vs ϕ space
- Observe **same damage constant** (=slope) for single crystal and poly



due to initial
traps in poly

800 MeV proton



24 GeV proton

Damage Curve Analysis

- Obtained radiation damage constants are compared to 24 GeV protons

Particle species	κ
24 GeV protons	1.0
800 MeV protons	1.67 ± 0.09
70 MeV protons	2.48 ± 0.25
Fast neutrons	4.5 ± 0.4

Damage Curve Analysis

- Obtained radiation damage constants are compared to 24 GeV protons
- Combined damage curve

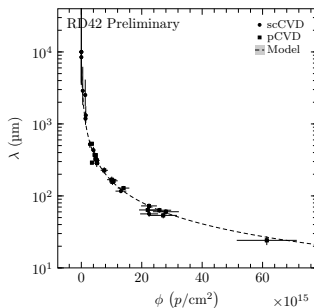
- Shift pCVD sample by

$$\phi_{0,i} = \frac{1}{\lambda_{0,i} k_i}$$

- Scale fluence by relative k

$$\phi_{\text{eq.}} = \frac{k_i}{k_{24 \text{ GeV protons}}} \times \phi_i$$

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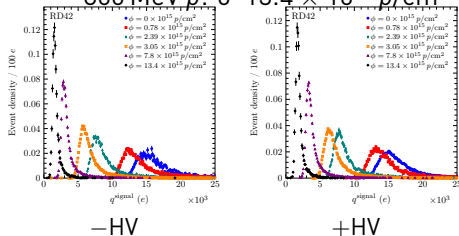


Signal Shape Analysis

- Study the shape of the pulse height distribution after irradiation

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800 MeV p : $0 - 13.4 \times 10^{15} \text{ p/cm}^2$

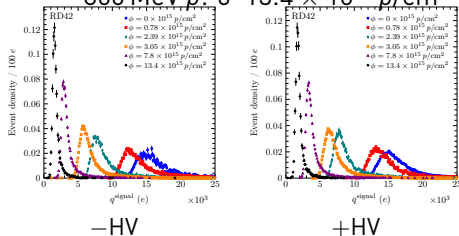


Signal Shape Analysis

- Study the shape of the pulse height distribution after irradiation
- To compare pCVD and sCVD samples: *FWHM/MP*

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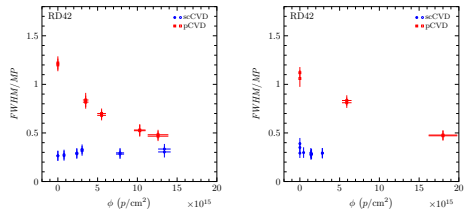
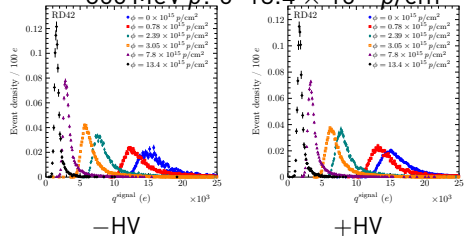


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800 MeV p : $0 - 13.4 \times 10^{15} \text{ p/cm}^2$

- Study the shape of the pulse height distribution after irradiation
- To compare pCVD and sCVD samples: *FWHM/MP*
- 800 MeV irradiated
 - pCVD samples
 - *FWHM/MP* decreases with dose
 - sCVD samples
 - Smaller initial *FWHM/MP*
 - *FWHM/MP* is flat with dose
- Similar results for other irradiation energies and species



800 MeV p

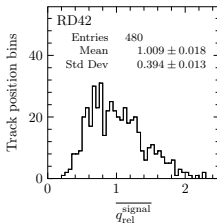
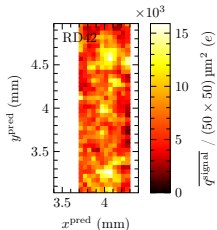
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Uniformity in pCVD Diamond [DOI: 10.1088/1361-6463/ab37c6]

- *FWHM/MP* before and after irradiation

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- *FWHM/MP* before and after irradiation
- Observe regions of different signal (λ) in unirradiated poly-crystalline diamond



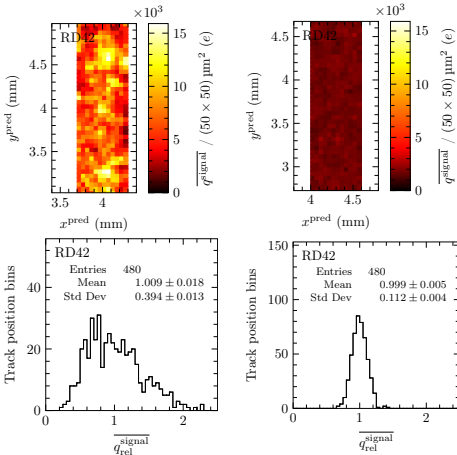
unirradiated

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- Derivative of damage equation:

$$\frac{d\lambda}{d\phi} = -k\lambda^2$$

→ Portions of material with the largest λ are damaged most for given fluence $d\phi$



unirradiated

$\phi = 18 \times 10^{15} p/\text{cm}^2$

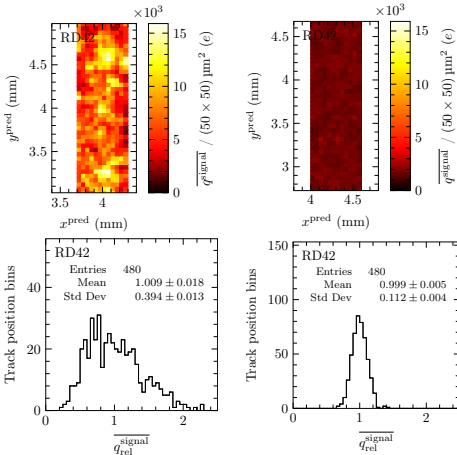
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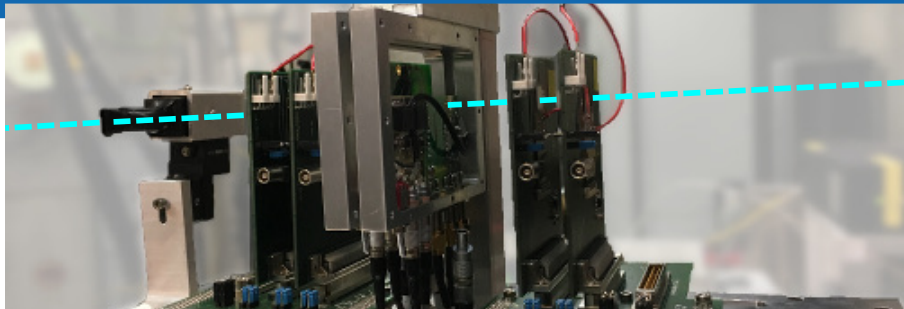
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- *FWHM/MP* is a **measure of the uniformity** of the material



unirradiated

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Rate Studies

Study the pulse height dependance on the particle flux

Setup

- Characterization in 260 MeV π^+ beam at PSI

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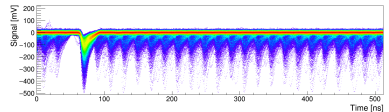
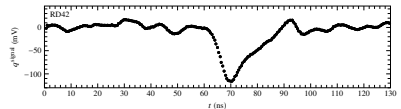
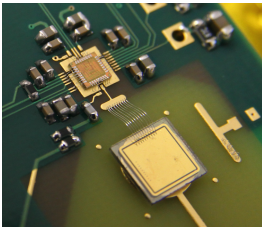
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- Recently measured rate dep. after fluences [up to \$8 \times 10^{15}\$ n/cm²](#)

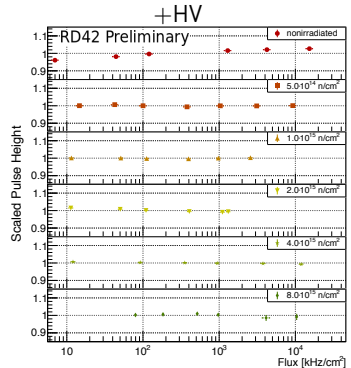
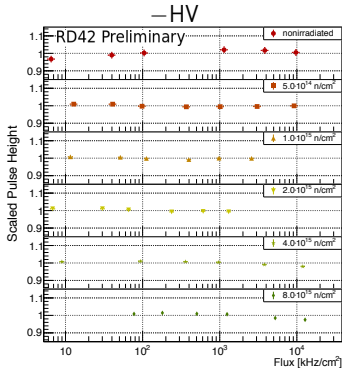
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- Began program to measure **rate dependance of irradiated devices**
- Recently measured rate dep. after fluences **up to 8×10^{15} n/cm²**
- Irradiated pad detectors tested in ETH (CMS Pixel) telescope



19.8 ns bunch spacing clearly visible

Rate Studies



- No rate dependence ($< 2\%$) observed in irradiated pCVD up to $10\text{--}20 \text{ MHz/cm}^2$
- No rate dependence ($< 2\%$) observed in irradiated pCVD up to $8 \times 10^{15} \text{ n/cm}^2$

Summary

- Quantified understanding of radiation effects
 - Measured [radiation tolerance](#) up to fluences of $10^{16}/\text{cm}^2$ (relevant for tracker application in [HL-LHC experiments](#))
 - Measured signal uniformity of single- and poly-crystalline CVD diamond up to fluences of $10^{16}/\text{cm}^2$
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 - Radiation damage studies were **recently published** in J. Phys. D: Appl. Phys. [DOI: 10.1088/1361-6463/ab37c6]
- Expanded understanding of rate effects @2 V/ μm
 - Irrad. pCVD diamond shows **no rate effect (<2%)** up to $20 \text{ MHz}/\text{cm}^2$
 - Irrad. pCVD diamond shows **no rate effect (<2%)** up to $8 \times 10^{15} \text{ n}/\text{cm}^2$

Backup

CCD vs Schubweg

CCD vs mean free drift distance before being trapped in an infinite material

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